

Notice of References Cited

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Applicant(s)/Patent Under

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Examiner

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Art Unit

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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,430,511 B1	08-2002	Tour et al.	702/19
*	B US-2003/0142440 A1	07-2003	Clinton et al.	360/123
*	C US-2003/0123189 A1	07-2003	Sato et al.	360/234.5
*	D US-2004/0214367 A1	10-2004	Segal et al.	438/053
*	E US-2004/0201930 A1	10-2004	Yoshikawa et al.	360/324.1
*	F US-2004/0264064 A1	12-2004	Sakakima, Hiroshi	360/322
*	G US-6,828,039 B2	12-2004	Sugawara, Takahiko	428/621
*	H US-6,833,980 B1	12-2004	Tsukagoshi et al.	360/324
*	I US-2005/0068679 A1	03-2005	Chen, Ga-Lane	360/131
*	J US-6,917,493 B2	07-2005	Clinton et al.	360/125.02
*	K US-6,920,014 B2	07-2005	Sato et al.	360/234.5
*	L US-2006/0092542 A1	05-2006	Ushida et al.	360/059
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	JP 2004221442 A	08-2004	Japan	SUGAWARA, TAKAHICO	H01L 43/08
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
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